Form PTO-1449						ATTY. DOCKET NO. M140-382			SERIAL NO. 10/705,685		
US PERARTMENT OF COMMERCE OATE T AND TRADEMARK OFFICE						APPLICANT JOHN R. TUTTLE					
SEP 192	CEP 1 9 7005			D BY APPLICANT ts if necessary)		FILING DATE NOV. 10, 2003			GROUP 2632		
& TRADEN	ALL CO		U.S	. PATENT DOCUME	NTS					•	
Examiner Initial		Document Number	Date	Name	-	Class	Su	belass	Filing Date If Appropriate		
	A										
	Al	3									
	AC		·			-					
	AE				•		<u> </u>				
<u> </u>	AI						-		·	-	
	AF								<del>  .</del>		
	AC	:					-				
	<u> </u>		FOREI	I GN PATENT DOCUI	MENTS						
		Document	Date	Country		Class	Sub	class	Translation		
	Number								Yes	No	
71	AH	DE 41 20 265 A1	6/1991	Germany (Mitsubish See US 5,274,221 (p. cited)			7/01		Abs		
	AJ	GB 1 567 784	5/1980	United Kingdom		G06K	19/00				
	AK	JP 1-191082	8/1989	Japan (Sony Corp.)		G01S	013/74		Abs		
77/	<b>ブル</b>   AL   JP 2-36476			Japan (Fijitsu Ltd)			015/		Abs		
			· · · · · · · · · · · · · · · · · · ·	cluding Author, Title,						-	
TN	Mount 1 echnology, pp. 19-20 (1/1992)										
	AN	IOHNSON, R.W., "Polymer Thick Films: Technology and Materials", Circuits Manufacturing (reprint), 4 pages (7/1982)									
	AO	GILLEO, K., "Using SM Devices on Flexible Circuitry", ELECTRI-ONICS, pp. 20-23 (3/1986)									
TN	AP	Chemical Society, pp. 36-54 (12/1990)									
EXAMINER DATE CONSIDERED											
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.											
11/15/05											

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

AP

DATE CONSIDERED

**EXAMINER**